## Notice of References Cited Application/Control No. | Applicant(s)/Patent Under Reexamination CHEN ET AL. | Examiner | Art Unit | Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-6,437,240 B2	08-2002	Smith, John W.	174/52.2
	В	US-6,737,750 B1	05-2004	Hoffman et al.	257/777
	С	US-6,518,666 B1	02-2003	Ikeda, Hironobu	257/738
	D	US-6,777,819 B2	08-2004	Huang, Chien-Ping	257/796
	Е	US-6,191,360 B1	02-2001	Tao et al.	174/52.4
	F	US-6,734,552 B2	05-2004	Combs et al.	257/707
	G	US-6,784,541 B2	08-2004	Eguchi et al.	257/723
	Н	US-6,486,554 B2	11-2002	Johnson, Eric Arthur	257/738
	ŀ	US-6,288,900 B1	09-2001	Johnson et al.	361/705
	J	US-5,726,079	03-1998	Johnson, Eric Arthur	438/106
	К	US-			
	L	US-			
	М	US-			

## **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP02000195994A	07-2000	Japan	Nishioka et al.	
	0					
	Р					
	ø					
	R					
	s					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	٦	
	>	
	8	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.